

AGH UNIVERSITY OF SCIENCE AND TECHNOLOGY

# **FEB** noise measurements

Aleksandra Molenda

27.10.2020

On behalf of AGH group, in collaboration with UJ group

Panda Collaboration Meeting 20/3, 26-30.10 2020 Darmstadt GSI Germany



### **FEB** overview

Front-end Electronics Board (FEB) is used to read straw tubes in STT and FT detectors. It contains:

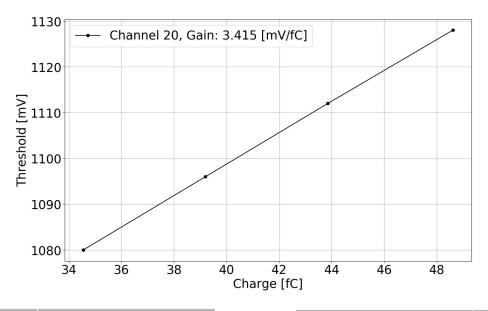
- 2 PASTTREC ASICs with 8 channels per ASIC (16 channels per FEB). Each ASIC includes:
  - One global threshold set for all channels,
  - 5-bit baseline DAC for each channel (from -30 mV to 30 mV, with 2mV step)
  - Gain setup (0.67,1,2,4 [mV/fC]),
  - Peaking-time setup (10,15,20,35 [ns])





# Noise units at gain set to 4 mV/fC

In front-end electronics read-out systems noise is usually presented in  $e^{-}$  (1  $e^{-}$  = 1.602·10<sup>-19</sup> C)



[e <sup>-</sup> ]	[mV]
1000	0,55
2000	1,09
3000	1,64
4000	2,19

[mV]	[e <sup>-</sup> ]
0,5	915,18
1	1830,35
2 (DAC step)	3660,71
3	5491,06



## Measurement setup

#### Most of the measurements were done for:

- Gain 4 mV/fC
- Peaking time 20 ns,
- Threshold 1.128 V (Vref = 1 V, threshold\_cfg = 64)
- FEB with Cout = 12 pF (needed for PASTTREC stability),
- The signal of 300 kHz frequency was injected from generator (from 0.1 to 1 V with step 1 mV).

#### Injection boards:

- Voltage divider (47 + 1 Ω resistors)
- Injection through 10 pF capacitor
- Injection to only one channel.

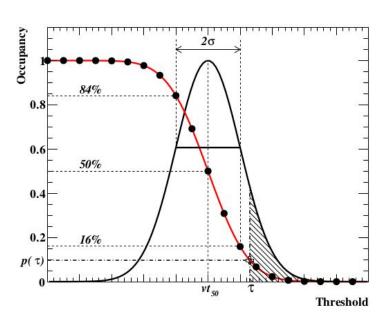


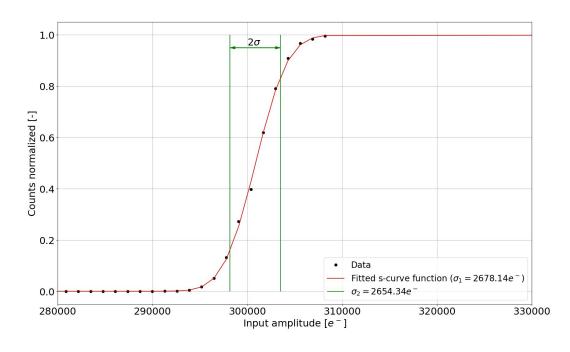
In case different setting are used, it is shown in description.



#### Noise calculations from s-curve

Noise is calculated assuming that number of counts vs signal amplitude (s-curve) behaves as erfc complementary error function.





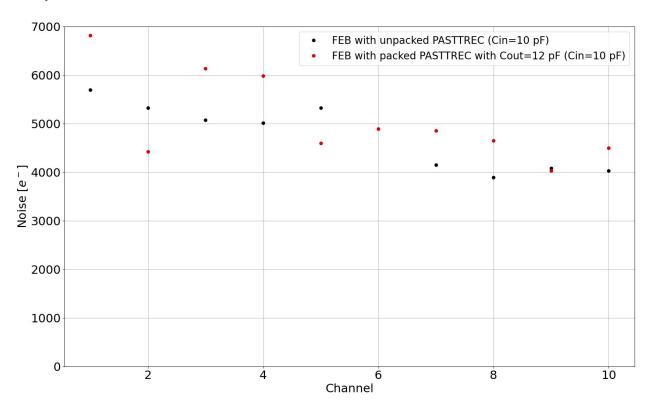
[1] Gonzalez-Sevilla, S. and others, *Electrical results of double-sided silicon strip modules for the ATLAS Upgrade Strip Tracker*, ATL-UPGRADE-PUB-2012-002, ATL-COM-UPGRADE-2012-008", May 2012

For standard analysis the input amplitude difference between the 84% and 16% is taken as  $2\sigma$ .



# Packed and unpacked ASIC comparison

Comparison of packed and unpacked ASIC was done during first measurements when the setup was not very stable yet.

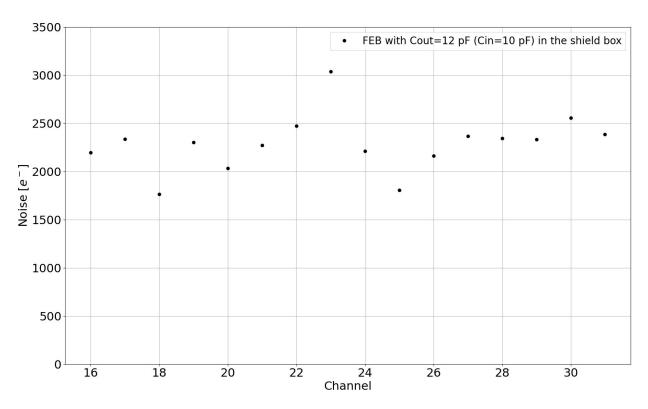


No significant difference between packed and unpacked ASIC is observed.



## FEB in the shield box

First measurements were done for FEB without connected detector in the shield box.



Noise about 2300 e<sup>-</sup>,



## Measurements with detector



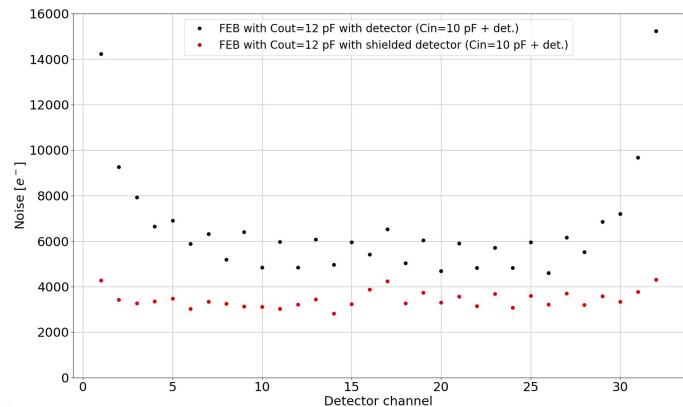
# Shielded detector measurement:

- slightly bigger noise for edge channels,
- no difference between top and bottom straws,
- noise about 3500 e<sup>-</sup>

# Even channels – bottom straws, odd channels – top straws.

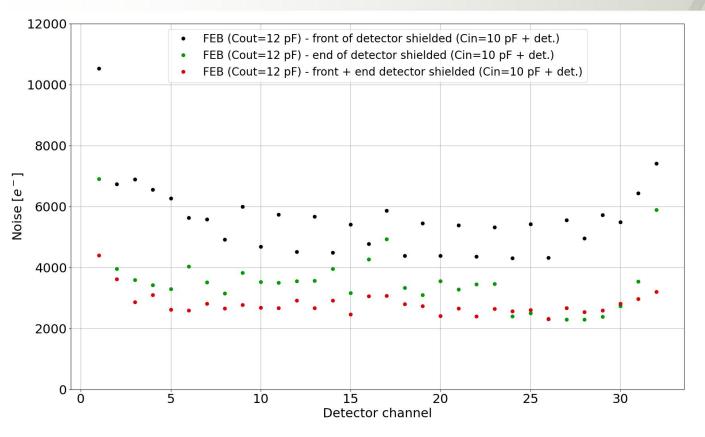
#### **Detector without a shield measurement:**

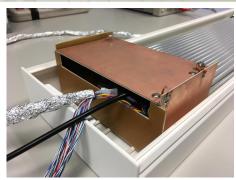
- bigger noise for edge channel,
- difference between bottom and top channels (bottom with bigger noise),
- noise about 5700 e<sup>-</sup> for middle channels,





# Measurements with detector + input capacitance Shielding of detector tests





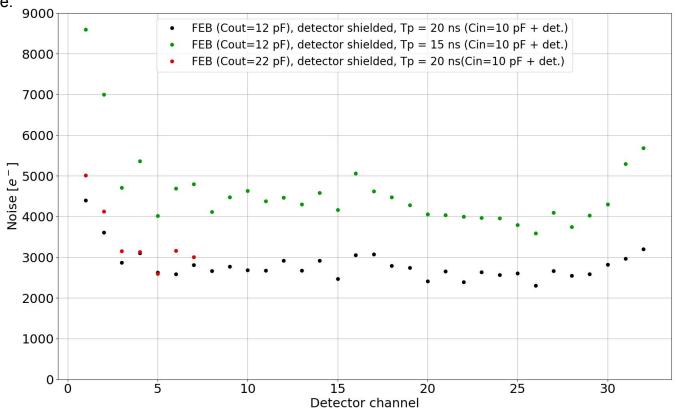


- Only front shielded: noise about 5500 e<sup>-</sup>, still big noise for edge channels and difference between top (odd) and bottom (even) straws (bottom ones have bigger noise),
- Only end shielded: noise about 3500 e<sup>-</sup>
- Both sides shielded: noise about 2600 e<sup>-</sup> for middle channels, slightly bigger values for edge channels
- Using conductive glue: more homogeneous channels



# Measurements with shielded detector + input capacitance

Both sides of detector shielded, straws with conductive glue. Measurement for different peaking time and output capacitance.



- Noise about 2600 e<sup>-</sup> for FEB with Cout=12 pF, bigger values for edge channels,
- Bigger noise for 15 ns peaking time about 4200 e<sup>-</sup> (about 1600 e<sup>-</sup> bigger)
- Slightly bigger noise for some channels for FEB with Cout=22 pF.



## Conclusions

#### Summary:

- The best results of noise level when both sides of detector are shielded (about 2600 e<sup>-</sup>) develop of the shield part,
- Larger noise with 15 ns peaking time but still on the reasonable level.

#### Future measurement plans:

- Optimization of the baseline setup,
- Homogeneity of channels.